

## **IN THE SPECIFICATION:**

On page 3, after paragraph 0013, insert the following summary of the invention:

### **Brief Summary of the Invention**

The method reduces computational resources in characterizing a parameter for a combination of an input pin and an output pin of a cell, the cell being contained in a library used in the design of an integrated circuit. The method includes: determining a worst case vector, wherein the worst case vector represents a set of input bits, with each of the input bits being applied to a corresponding one of a set of input pins wherein the corresponding one is other than the input pin of the combination, wherein the worst case vector would cause propagation of most noise from the input pin to the output pin among vectors which would cause a bit value transition on the output pin if the input bit value is changed on the input pin; computing a plurality of data values for the parameter when the worst case vector is applied to the set of input pins, wherein the plurality of data values are used in an analysis of the integrated circuit irrespective of which of the vectors is applied to the set of input pins; and wherein the parameter comprises noise immunity, wherein a failure result is deemed to be obtained for an input glitch of a first height and a first width if the height of an output glitch corresponding to the input glitch exceeds a first threshold voltage, and a success result is deemed to be obtained otherwise, the method further includes generating a noise immunity curve (NIC) corresponding to only the worst case vector, wherein the NIC contains a plurality of immunity transition points, wherein each of the plurality of immunity transition points indicates a minimum value for one dimension of the input glitch required for the failure result for each of a value of the other dimension.